

# Military CMOS Programmable Gate Array Logic Cell™ Array M2064/M2018

Conforms to MIL-STD-883, Class B\*

## Features

### CMOS

- Low power
- TTL or CMOS input threshold levels

### PROGRAMMABLE

- Programmable Logic functions
- Programmable I/O blocks
- Programmable interconnects

### STATIC RAM BASED

- Reprogrammable
- Reconfigurable

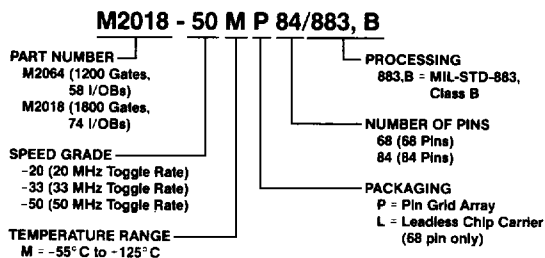
### SECURITY

- User selectable Security Mode
- Verification feature

## Benefits

- Reduced power supply
- Higher board densities
- Complete user control of design
- Instant prototyping
- Replaces SSI and MSI devices
- Easy design modification
- Selectable configuration modes
- 100% testable
- Protects proprietary designs
- Eases design debug

## Ordering Information



writable storage cells with the configuration data. The reprogrammability of the SRAM-based LCA allows instant design modification on the bench and on the board. Due to the SRAM-based architecture of the LCA, the radiation tolerance data for the M2064 is similar to industry SRAMs which display Total Dose levels from  $10^4$  to  $10^6$  rads (Si).

Applications for the LCA cover a wide spectrum of uses. With its high gate density and low-power CMOS technology, the LCA is an ideal low-cost gate array good for prototyping as well as production. The LCA's SRAM-based architecture allows it to be used in applications that take advantage of its reconfigurability. Ground systems (radar) can use the LCA as reconfigurable hardware replacing several devices and saving board space. The SRAM-based logic of the LCA allows for pattern security of sensitive designs when the device is removed from its board. When a different mode backup device is needed the LCA provides excellent redundancy. In short, the LCA offers the total ASIC solution.

## Description

The Military CMOS Logic Cell Array bridges the gap between Programmable Logic Devices (PLDs) and gate arrays. This high-density, low-power Logic Cell Array device provides designers with both the density benefits of gate arrays and the programmability benefits of user-configurable devices.

The flexible architecture of the LCA is similar to that of a gate array, with an interior matrix of programmable logic blocks called Configurable Logic Blocks (CLBs), a surrounding ring of programmable I/O blocks (IOBs) and programmable interconnects used to define the overall device structure. Unlike gate arrays, LCA functionality is user defined by loading the internal

## Silicon Menu

MMI PART	ORGANIZATION	EQUIVALENT GATE COUNT	CONFIGURABLE LOGIC BLOCKS	USER I/Os	CONFIGURATION PROGRAM BITS	MAX STANDBY CURRENT (CMOS INPUTS)	MAX STANDBY CURRENT (TTL INPUTS)	PACKAGES	MAX TOGGLE RATE BETWEEN CLBs
M2064-20	8x8	1200	64	58	12040	5 mA	10 mA	68LCC, 68PGA	20 MHz
M2064-33	8x8	1200	64	58	12040	5 mA	10 mA	68LCC, 68PGA	33 MHz
M2064-50	8x8	1200	64	58	12040	5 mA	10 mA	68LCC, 68PGA	50 MHz

\* Latest revision.

10331A  
JANUARY 1988

# Military M2064/M2018

## Software/Hardware Menu

MMI PARTS	
LCA-MDS21	LCA Development System
LCA-MSC21	LCA Development System Annual Support Agreement
LCA-MDS22	LCA Simulator (P-SILOS™)
LCA-MDS23	LCA Automatic Placement and Routing Program
LCA-MDS24	LCA In-Circuit Emulator

MMI PARTS	
LCA-MDS28	LCA Universal Pod
LCA-MDS27XX	LCA Package Specific Pod Headers
LCA-MDS31	LCA Futurenet® Interface
LCA-MDS33	LCA Daisy Interface
LCA-MDS34	LCA Mentor Interface
LCA-MDSXX	LCA/OrCAD™ Package
LCA-MEK01	LCA Evaluation Kit

## Absolute Maximum Ratings

Supply voltage, $V_{CC}$	-0.5 V to 7.0 V
Power down, $V_{CC}$	2.0 V to 7.0 V
Input voltage range	-1.5 V to 5.5 V
Voltage applied to three-state output	-0.5 V to 5.5 V
Storage temperature	-65°C to +150°C
Terminal temperature, Leadless Chip Carrier package (Soldering, 10 seconds)	240°C
Thermal resistance, junction to case, $\theta_{jcm}$ , and junction to ambient, $\theta_{jam}$	

Package	$\theta_{jcm}$	$\theta_{jam}$ (Still air)
(L) Leadless Chip Carrier	1.5°C/W	32°C/W
(P) Pin Grid Array	3°C/W	45°C/W

Maximum power dissipation	See Table 2
Maximum junction temperature	175°C
Maximum current density	Contact factory

## Operating Conditions

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
$V_{CC}$	Supply voltage relative to GND	4.5		5.5	V
$V_{IHT}$	High level input voltage—TTL configuration	2.0		$V_{CC}$	V
$V_{IHC}$	High level input voltage—CMOS configuration	0.7 $V_{CC}$		$V_{CC}$	V
$V_{ILT}$	Low level input voltage—TTL configuration	0		0.8	V
$V_{ILC}$	Low level input voltage—CMOS configuration	0		0.2 $V_{CC}$	V
$I_{IT}$	Input leakage current—TTL configuration	±1			μA
$I_{IC}$	Input leakage current—CMOS configuration	±1			μA
$I_{OZ}$	Three-state output off current ( $V_{CC} = 5.5$ V)	±10			μA
$t_{OP}$	Operating free-air temperature	-55		+125	°C

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## Electrical Characteristics Over Operating Conditions

Conforms to MIL-STD-883 Group A  
Subgroups 1, 2 and 3

SYMBOL	PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
$V_{OH}$	High level output voltage	$V_{CC} = \text{MIN}$ $I_{OH} = -4.0$ mA	3.7			V
$V_{OL}$	Low level output voltage	$V_{CC} = \text{MIN}$ $I_{OL} = 4.0$ mA			0.4	V
$I_{CCO}$	Quiescent operating power supply current	CMOS inputs	$V_{CC} = 5.0$ V		5	mA
		TTL inputs	$V_{CC} = 5.0$ V		10	mA
$I_{CCPD}$	Power down supply current	$V_{CC} = 2.0$ V			0.5	mA

## Power On Timing

The LCAs contain on-chip reset timing logic for power-up operation. To insure proper master mode system operation, VCC must rise from 2.0 V to minimum specification level in 10 ms or less. For other modes, initiation of configuration must be

delayed for 60 ms after VCC reaches the minimum specified level.

## Test Conditions

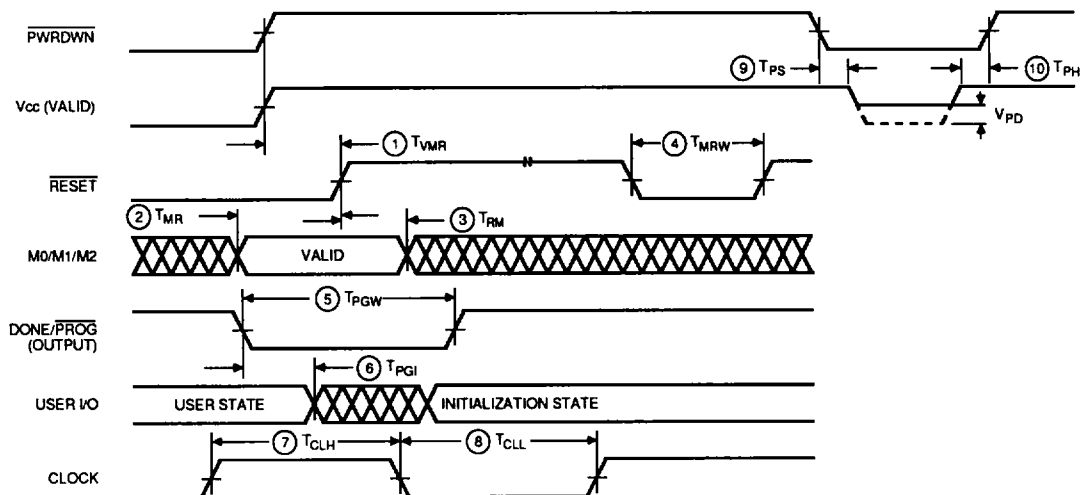
Outputs loaded with rated DC current and 50-pF capacitance to GND.

## Switching Characteristics – General

Conforms to MIL-STD-883 Group A  
Subgroups 9, 10 and 11\*

SYMBOL	DESCRIPTION	-20		-33		-50		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_{VMR}$ ①	$\overline{RESET}$		V <sub>CC</sub> setup (2.0 V)	250	150	150		ns
$t_{MR}$ ②	$\overline{RESET}$		M2, M1, M0 setup	100	60	60		ns
$t_{RM}$ ③	$\overline{RESET}$		M2, M1, M0 hold	100	60	60		ns
$t_{MRW}$ ④	$\overline{RESET}$		Width (LOW)	250	150	150		ns
$t_{PGW}$ ⑤	DONE/ PROG		Program width (LOW)	6	6	6		μs
$t_{PGI}$ ⑥	DONE/ PROG		Initialization		7		7	μs
$t_{CLH}$ ⑦	CLOCK		Clock (HIGH)	20	12	8		ns
$t_{CLL}$ ⑧	CLOCK		Clock (LOW)	20	12	8		ns
$t_{PS}$ ⑨	$\overline{PWR\ DWN}$		Setup to V <sub>CC</sub>	0	0	0		ns
$t_{PH}$ ⑩	$\overline{PWR\ DWN}$		Hold from V <sub>CC</sub>	0	0	0		ns
V <sub>PD</sub>	$\overline{PWR\ DWN}$		Power Down	2.0	2.0	2.0		V

- Notes: 1. V<sub>CC</sub> must rise from 2.0 Volts to V<sub>CC</sub> minimum in less than 10 ms for master mode  
 2. RESET timing relative to power-on and valid mode lines (M0, M1, M2) is relevant only when RESET is used to delay configuration.  
 3. Minimum CLOCK widths for the auxiliary buffer are 1.25 times the t<sub>CLH</sub>, t<sub>CLL</sub>.  
 \* Contact factory for test macros.



**Switching Characteristics – CLB**

SYMBOL	DESCRIPTION		-20		-33		-50		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>ILO</sub> ①	Logic input to output	Combinatorial		35		20		15	ns
t <sub>ITO</sub> ②		Transparent latch		45		25		20	ns
t <sub>ALO</sub>		Additional for Q through F or G to out		30		13		8	ns
t <sub>CKO</sub> ③	K Clock	To output		35		20		15	ns
t <sub>ICK</sub> ④		Logic-input setup	22		12		8		ns
t <sub>CKI</sub> ⑤		Logic-input hold	0		0		0		ns
t <sub>CCO</sub> ⑩	C Clock	To output		45		25		19	ns
t <sub>ICC</sub> ⑥		Logic-input setup	18		12		9		ns
t <sub>CCI</sub> ⑦		Logic-input hold	10		6		0		ns
t <sub>CIO</sub> ⑪	Logic input to G Clock	To output		65		37		27	ns
t <sub>ICI</sub> ⑧		Logic-input setup	10		6		4		ns
t <sub>CII</sub> ⑨		Logic-input hold	15		9		5		ns
t <sub>RIO</sub> ⑫	Set/reset direct	Input A or D to out		45		25		22	ns
t <sub>RLO</sub> ⑬		Through F or G to out		65		37		28	ns
t <sub>MRQ</sub>		Master Reset pin to out		60		35		25	ns
t <sub>RS</sub>		Separation of set/reset	30		17		9		ns
t <sub>RPW</sub>		Set/reset pulse-width	20		12		9		ns
F <sub>CLK</sub>	Flip-flop toggle rate	Q through F to flip-flop	20		33		50		MHz
t <sub>CH</sub> ⑭	Clock	Clock HIGH	20		12		8		ns
t <sub>CL</sub> ⑮		Clock LOW	20		12		8		ns

Note: All switching characteristics apply to all valid combinations of process, temperature and supply

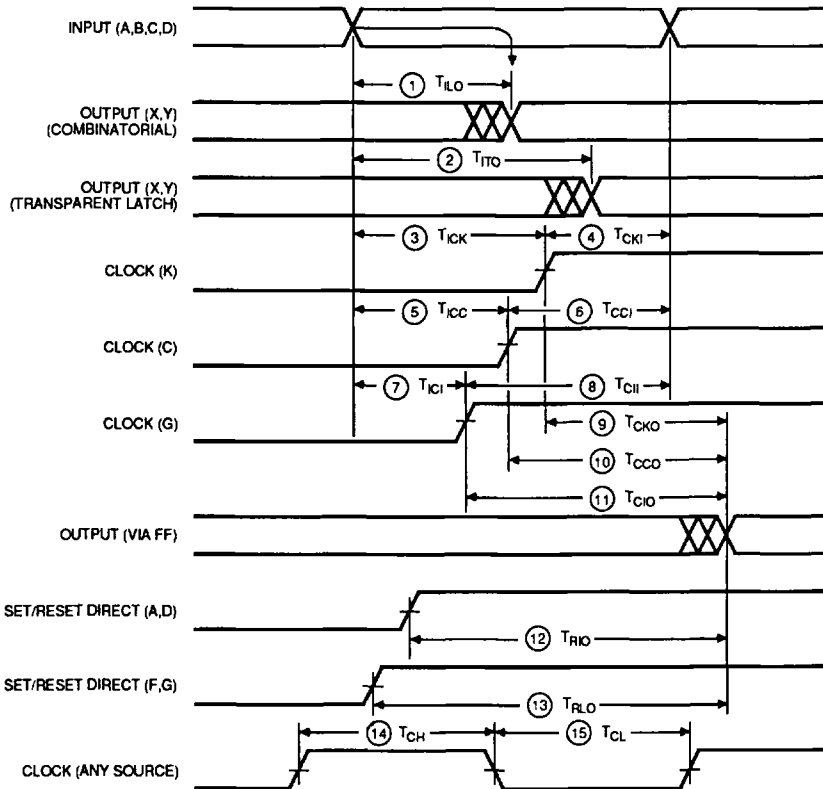
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**Military Case Outlines\***

PACKAGE OUTLINE LETTER	CONFORMS TO MIL-M-38510 APPENDIX C CASE
L	C-7
P	P-BC

\* Refer to MIL-M-38510, Appendix C for the appropriate package drawings

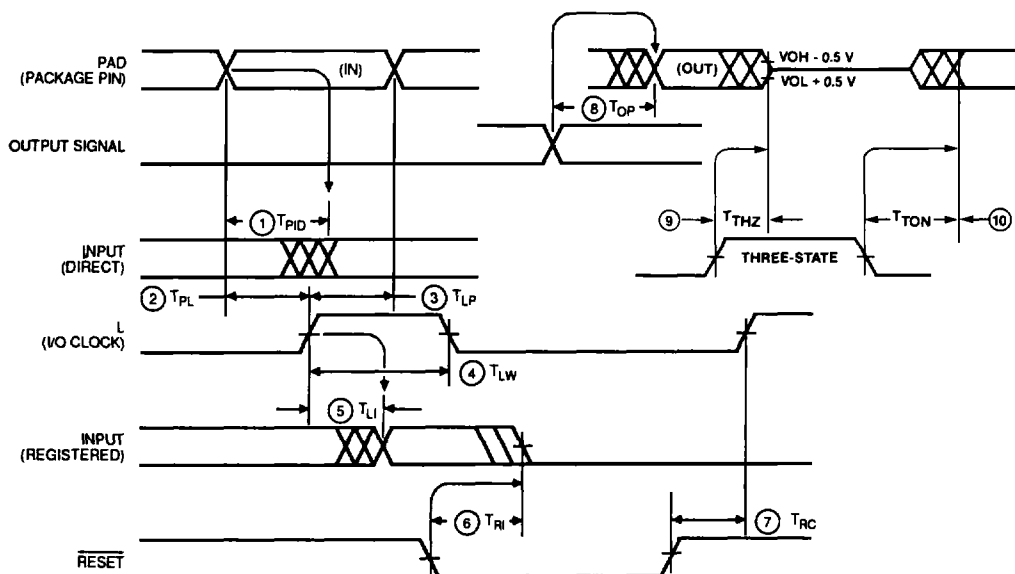
Switching Characteristics CLB



Switching Characteristics — IOB

SYMBOL	DESCRIPTION	-20		-33		-50		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_{PID}$ ①	Pad (package pin) to input (direct)		20		12		8	ns
$t_{LI}$ ⑤	I/O Clock to input (storage)		30		20		15	ns
$t_{PL}$ ②	I/O Clock to pad-input setup	20		12		8		ns
$t_{LP}$ ③	I/O Clock to pad-input hold	0		0		0		ns
$t_{LW}$ ④	I/O Clock pulse width	20		12		9		nsp
	I/O Clock frequency		20		33		50	MHz
$t_{OP}$ ⑧	Output to pad (output enabled)		25		15		12	ns
$t_{THZ}$ ⑨	Three-state to pad begin hi-Z		35		25		20	ns
$t_{TON}$ ⑩	Three-state to pad end hi-Z		40		25		20	ns
$t_{RI}$ ⑥	RESET to input (storage)		50		40		30	ns
$t_{RC}$ ⑦	RESET to input clock		35		35		25	ns

Note: Timing is measured at 0.5 V<sub>CC</sub> levels with 50-pF output load.

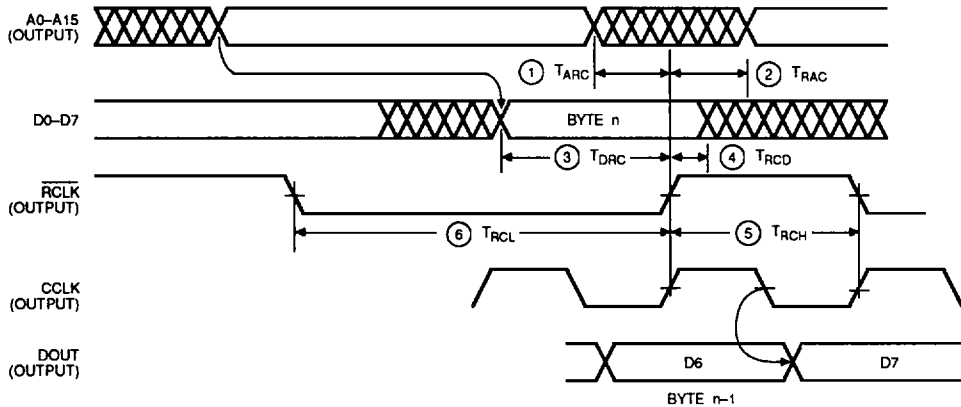


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**Switching Characteristics – Programming – Master Mode**

SYMBOL	DESCRIPTION	-20		-33		-50		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_{ARC}$ ①	RCLK	From address invalid		0	0	0	0	ns
$t_{RAC}$ ②		To address valid		300	200	200	200	ns
$t_{DRC}$ ③		To data setup		100	60	60	60	ns
$t_{RCD}$ ④		To data hold		0	0	0	0	ns
$t_{RCH}$ ⑤		RCLK HIGH		600	600	600	600	ns
$t_{RCL}$ ⑥		RCLK LOW		4.0	4.0	4.0	4.0	$\mu$ S

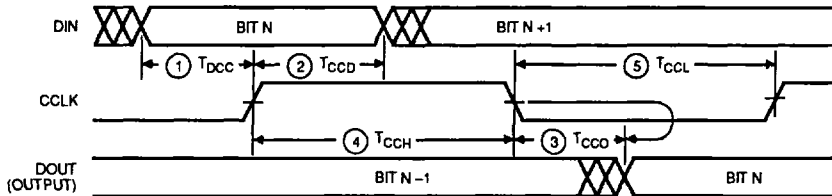
- Notes 1. CCLK and DOUT timing are the same as for slave mode  
 2. At power up,  $V_{CC}$  must rise from 2.0 V to  $V_{CC}$  minimum in less than 10 ms



**Switching Characteristics – Programming – Slave Mode**

SYMBOL	DESCRIPTION	-20		-33		-50		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_{CCO}$ ①	CCLK to DOUT		100		65		65	ns
$t_{DCC}$ ①	CCLK DIN setup	50		25		0		ns
$t_{CCD}$ ②	CCLK DIN hold	75			40		40	ns
$t_{CCH}$ ④	CCLK HIGH time	0.50		0.30		0.25		$\mu$ S
$t_{CCL}$ ③	CCLK LOW time	0.30	10.0	0.25	5.0	0.25	5.0	$\mu$ S
$F_{CC}$	CCLK frequency		1		2		2	MHz

Note: Configuration must be delayed at least 40 ms after VCC minimum.

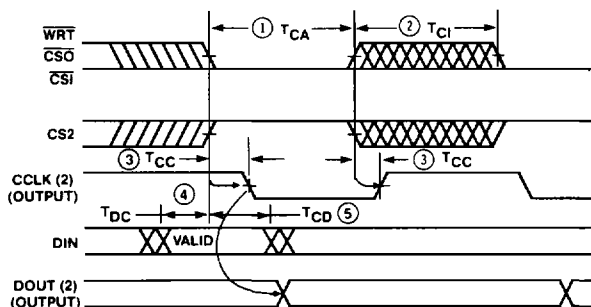




**Switching Characteristics – Programming – Peripheral Mode**

SYMBOL	DESCRIPTION	-20		-33		-50		UNIT		
		MIN	MAX	MIN	MAX	MIN	MAX			
$t_{CA}$ ①	Controls <sup>1</sup> (CS0, CS1, CS2, WRT)	Active (last active input to first inactive)		0.30	10.0	0.25	5.0	0.25	5.0	$\mu$ s
$t_{CI}$ ②		Inactive (first inactive input to last active)		0.25		0.25		0.25		$\mu$ s
$t_{CCC}$ ③		CCLK <sup>2</sup>			100		75		75	ns
$t_{DC}$ ④		DIN setup		50		35		35		ns
$t_{CD}$ ⑤		DIN hold		10		5		5		ns

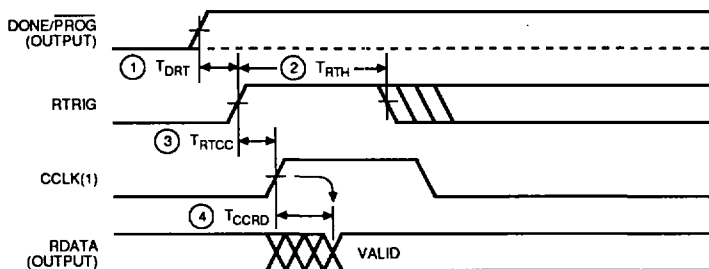
- Notes: 1. Peripheral mode timing determined from last control signal of the logical AND of (CS0, CS1, CS2, WRT) to transition to active or inactive state  
 2. CCLK and DOUT timing are the same as for slave mode  
 3. Configuration must be delayed at least 40 ms after  $V_{CC}$  minimum.



**Switching Characteristics – Program Readback**

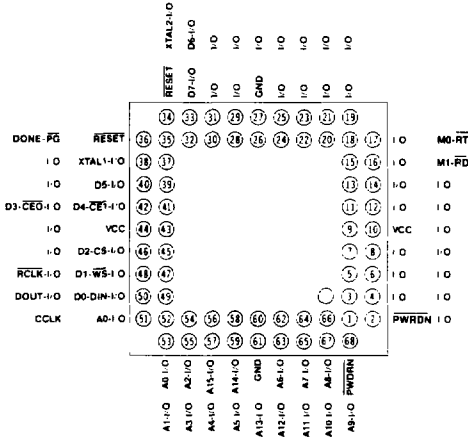
SYMBOL	DESCRIPTION	-20		-33		-50		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX		
$t_{DRT}$ ①	RTRIG	PROG setup		300		300		300	ns
$t_{RTH}$ ②		RTRIG HIGH		250		250		250	ns
$t_{RTCC}$ ③	CCLK	RTRIG setup		100		100		100	ns
$t_{CCRD}$ ④		RDATA delay			100		100		100

- Notes: 1. CCLK and DOUT timing are the same as for slave mode.  
 2. DONE/PROG output/input must be HIGH (device programmed) prior to a positive transition of RTRIG (M0).

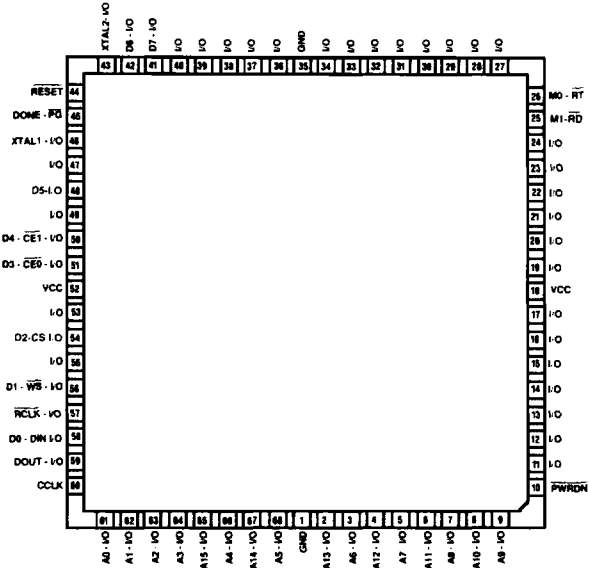


Device Pinouts\*

M2064  
Logic Cell Array  
68 Pin Grid Array  
Top View

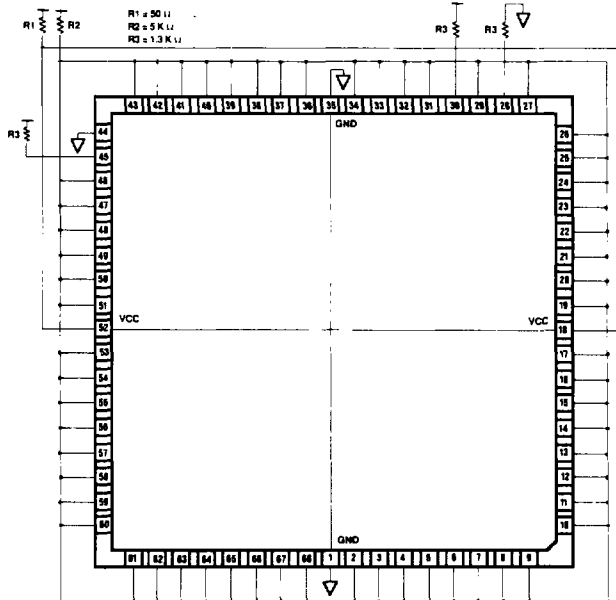


M2064  
Logic Cell Array  
68 Pin  
Leadless Chip Carrier



Burn-In Circuitry\*

Condition C  
Static Burn-In



Condition D  
Dynamic Burn-In  
Contact factory

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## Military M2064/M2018

### Configuration Pin Assignments\*

68-PIN LCC	68-PIN PGA	CONFIGURATION MODE: <M2: M1: M0>				USER OPERATION	
		SLAVE <1:1:1>	PERIPHERAL <1:0:1>	MASTER-HIGH <1:1:0>	MASTER-LOW <1:0:0>		
1	B6	GND				I/O	
2	A6	<HIGH>					
3	B5						A13 (O)
4	A5						A6 (O)
5	B4						A12 (O)
6	A4						A7 (O)
7	B3						A11 (O)
8	A3						A8 (O)
9	A2						A10 (O)
10	B2					PWRDWN (I)	
11	B1	<HIGH>					
12	C2						
13	C1						
14	D2						
15	D1						
16	E2						
17	E1	VCC				I/O	
18	F2	<HIGH>					
19	F1						
20	G2						
21	G1						
22	H2						
23	H1	M1 (HIGH)	M1 (LOW)	M1 (HIGH)	M1 (LOW)	RDATA (O)	
24	J2	M0 (HIGH)	M0 (HIGH)	M0 (LOW)	M0 (LOW)	RTRIG (I)	
25	J1	M2 (HIGH)				I/O	
26	K1	HDC (HIGH)					
27	K2	<HIGH>					
28	L2	LDC (LOW)					
29	K3	<HIGH>					
30	L3						
31	K4						
32	L4						
33	K5	<HIGH>					
34	L5	<HIGH>					

<HIGH> is high impedance with a 20 to 50-K $\Omega$  internal pull-up resistor during configuration

**Table 1. M2064 Pin Assignments  
(continued on next page)**

# Military M2064/M2018

## Configuration Pin Assignments\*

68-PIN LCC	68-PIN PGA	CONFIGURATION MODE: <M2: M1: M0>				USER OPERATION					
		SLAVE <1:1:1>	PERIPHERAL <1:0:1>	MASTER-HIGH <1:1:0>	MASTER-LOW <1:0:0>						
35	K6	GND				I/O					
36	L6	<<HIGH>>									
37	K7										
38	L7										
39	K8										
40	L8										
41	K9						D7 (I)				
42	L9						D6 (I)				
43	L10										XTL2 or I/O
44	K10						RESET (I)				
45	K11	DONE (O)				PROG (I)					
46	J10	<<HIGH>>				XTL1 or I/O					
47	J11										
48	H10					D5 (I)					
49	H11										
50	G10					$\overline{CS0}$ (I)	D4 (I)				
51	G11					$\overline{CS1}$ (I)	D3 (I)				
52	F10	VCC				I/O					
53	F11	<<HIGH>>									
54	E10						$\overline{CS2}$ (I)	D2 (I)			
55	E11										
56	D10						$\overline{WRT}$ (I)	D1 (I)			
57	D11						$\overline{RCLK}$				
58	C10	DIN (I)		D0 (I)							
59	C11	DOUT (O)									
60	B11	CCLK (I)	CCLK (O)			CCLK (I)					
61	B10	<<HIGH>>				A0 (O)					
62	A10					A1 (O)					
63	B9					A2 (O)					
64	A9					A3 (O)					
65	B8					A15 (O)					
66	A8					A4 (O)					
67	B7					A14 (O)					
68	A7					A5 (O)					

<<HIGH>> is high impedance with a 20 to 50-K $\Omega$  internal pull-up resistor during configuration

**Table 1. M2064 Pin Assignments**

\* Contact factory for M2018 pinout, burn in circuitry and pin assignments.

## Pin Description

### **PWRDWN**

An active low power-down input stops all internal activity to minimize VCC power and puts all output buffers in a high-impedance state. Configuration is retained, however, internal storage elements are Reset. When the PWRDWN pin returns HIGH, the device returns to operation with the same sequence of reset, buffer enable and DONE, PROGRAM as at the completion of configuration.

### **M0, RTRIG**

As Mode 0, this input and M1, M2 are sampled before the start of configuration to establish the configuration mode to be used.

As a read trigger, an input transition to a HIGH, after configuration is complete, will initiate a readback of configuration and storage element data. This operation may be limited to a single request, or be inhibited altogether, by selecting the appropriate readback option when generating the bit stream.

### **M1, RDATA**

As Mode 1, this input and M0, M2 are sampled before the start of configuration to establish the configuration mode to be used.

As an active-low read data; after configuration is complete, this pin is the output of the readback data.

### **M2**

As Mode 2, this input and M0, M1 are sampled before the start of configuration to establish the configuration, mode to be used. After configuration, this pin becomes a user-programmable I/O.

### **HDC**

High during configuration is held at a HIGH level by the LCA until after configuration. It is intended to be available as a control indication that configuration is not complete. After configuration, this pin is a user I/O.

### **LDC**

Low during configuration is held at a LOW level by the LCA until after configuration. It is intended to be available as a control indication that configuration is not completed. It is particularly useful in master mode as a LOW enable for an EPROM. After configuration, this pin is a user I/O. If used as a LOW EPROM enable, it should be programmed as a HIGH after configuration.

### **RESET**

This is an active-low input which has three functions. Prior to the start of configuration, a LOW input will delay the start of the configuration process. An internal circuit senses the application of power and begins a minimal time-out cycle on the order of 100 ms. When the time-out and RESET are complete, the levels of the "M" mode lines are sampled and configuration begins. If RESET is asserted during a configuration, the LCA is reinitialized and will restart the configuration at the termination of RESET. If RESET is asserted after configuration is complete, it will provide an asynchronous reset of all IOB and CLB storage elements of the LCA.

### **DONE, PROG**

The DONE open drain output is configurable with or without a pull-up resistor of about 3 K $\Omega$ . At the completion of configuration, the circuitry of the LCA becomes active in a synchronous order and one configuration clock cycle later DONE is asserted. Once configuration is done, a HIGH-to-LOW transition of this program pin will cause an initialization of the LCA and start a reconfiguration if that mode is selected in the current configuration.

### **XTL1**

This user I/O pin may be configured to operate as the output of an amplifier usable with an external crystal and bias circuitry to form an oscillator.

### **XTL2**

This user I/O pin may be configured to operate as the input of an amplifier usable with an external crystal and bias circuitry to form an oscillator.

### **CCLK**

During configuration, configuration clock is an output of an LCA in either master or peripheral mode. LCAs in slave mode use it as a clock input. During a readback operation, it is an input clock for the configuration data being output.

### **DOUT**

This user I/O pin is used during configuration to output serial configuration data out for daisy-chained slaves' data in.

### **DIN**

This user I/O pin is used as serial data in during slave or peripheral configuration. This pin is D0 in master configuration mode.

### **CS0, CS1, CS2, WRT**

These four inputs represent a set of signals, three active low and one active high, which are used in the peripheral mode to control configuration data entry. The assertion of all four generates a LOW CCLK and shifts DOUT data. The removal of any assertion clocks in the DIN data present and causes a HIGH CCLK. In master mode, these pins become part of the parallel configuration byte (D4, D3, D2, D1). After configuration is complete, they are user-programmed I/O.

### **RCLK**

During master mode configuration, this pin represents a read clock of an external memory device. After configuration is complete, this pin becomes a user-programmed I/O.

### **D0-D7**

This set of eight pins represents the parallel configuration data byte for the master mode. After configuration is complete, they are user-programmed I/O.

### **A0-A15**

This set of sixteen pins presents an address output for an external configuration memory during master mode. After configuration is complete, they are user-programmed I/O. A12 through A15 are not available in packages with less than sixty-eight pins.

### **I/O**

A pin which may be programmed by the user to be input and/or output following configuration. Some of these pins present a high-impedance pull-up or perform other functions before configuration is complete.